Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/936,565	SAUK, JOHN J.
Examiner	Art Unit

1643

Christopher H. Yaen

SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH N (INCLUDING SEAR)		)
	DATE	EXMR
Palm iventor search	2/16/2006	СНҮ
STIC seq search - enclosed	2/16/2006	СНҮ
West- enclosed	2/16/2006	СНҮ